

Functional IC Test Generating Software for Compact Professional Range

- Library development manager for IC configuration
- PLIP language for full generation of new IC functional tests
- Compiler, debugger and active help integrated
- Connection to PC via RS-232 or USB (with adapter)

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Name Copy of 74100 Function	INTERNAL AND	Family USER
Device Information   BFL Test   AICT Test   DispMast	ter Test   LinearMaster Test	
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Package CIL		Inne
	Pin No Pin Name VCC+ END VC	- High V
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	2 101	
Low Threshold 0.9V	3 102	
Open Collector Switch Theehold  1.2V	4 102	
OpenEniter High Threshold (2.4/	5 101	
Index Copy of 74100 Tech	6 NC 0 0	1 D Ac
Vanion 2.62	7 GND 🖸 🖸 🖸	
Date 28/07/2006	8 201 0 0	1 0 v 00
VPSAT -	E836	
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COMP_TEST_PASS -	EBAB	
FBRATIO -	EBAF	
FD_TEST_PASS -	E000	
VPLUS -	E887	
VMINUS -	E888	
VIEST -	EBOP	
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# **CompactLink Software**

A PC based software package that allows users to add new devices to the library and create functional tests to suit special applications.

New IC functional tests can be created using *PremierLink IC Programming* (PLIP), a high-level descriptive test programming language optimised for generation of both analogue and digital IC test programmes.

Thanks to the RS-232 link, software updates (available on the internet) can be downloaded and programmed into the Compact units. This active link also allows for live testing of new devices.





## **CompactLink Software**

#### Library Development Manager

The Library Development Manager displays all the devices added to the library and saved in the USER family.

All details are stored in the Microsoft Access<sup>TM</sup> compatible database file located in the PremierLink folder.

The device data is organised in 20 families and can be filtered using the drop down menus. A device name or function can also be typed in to facilitate the search. The list will be filtered to show only the entries containing the entered text. As an option, *intelligent sort* produces a more logical list by using the numeric part of the device name only.

Vame Copy of 74100	Function 8 BIT BISTABLE LATCH				Family U	SER	
evice Information BFL Test AICT Test Chip	oMaster Test   Line	sarMaster Test					
Device Info	Pin Out Numbe	erofpins: 24					
	Pin No	Pin Name	VCC+	GND	VCC-	High V	
	1	NC					Move
Llass Latch	2	1D1					
Tri State Low Threshold 0.5V	3	1D2					Move Down
Open Collector Switch Threshold 1.2V	4	102					
Open Emitter High Threshold 2.4V	5	101					
ndex Copy of 74100 Tech	- 6	NC					Add
Version 2.62	- 7	GND					
Date 28/07/2006	- 8	201					Delete

#### **Programming Interface**

The Programming Interface is designed for the generation and debugging of new functional IC tests. PLIP (PremierLink IC Programming) is a high level language designed specifically for test programming. The syntax is highly descriptive so that programmes are, to a large extent, self commenting. However, comments can also be inserted if required.

The built in compiler generates binary data which can be executed in stand alone form by the integral debugger or combined into library files for use with System8 products. Up to 3 breakpoints can be added to the programme where execution can be suspended and data can be examined. The debugger allows the user to identify and fix the possible problems in the programme, whilst connected to the hardware, before adding the new device to the library.

## **Device Definition**

When a device is selected or created, the device definition window appears. This allows the user to enter the information related to the device as well as define its physical characteristics. The name and function will be used by the database for sorting. Parameters such as package, class, thresholds and output types may also be selected.

The power and ground pins of the new device must be specified using the pin out table.





## **Online Active Help**

CompactLink is supplied with an extensive online active help which can be accessed at any time during programming. This facility provides the user with a PLIP syntax guide for each command. The Active Help window is broken down into :

- A syntax section
- An extensive description of the command
- Concrete examples for illustration
- Additional comments (if applicable)
- Target field



Making Light Work

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## **Functional IC Test Generator**